

In Situ SEY Measurements in CsrTA

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Measuring secondary electron yields (SEYs) on technical surfaces in accelerator vacuum systems provides essential information for many accelerator R&D projects, such as the ILC Damping Rings, regarding to electron cloud growth and suppression. As a part of CsrTA research program, we developed and deployed SEY in-situ measurement systems. Two such SEY systems were installed to expose samples with direct and scattered synchrotron radiation (SR), and the SEYs of the samples were measured as a function of SR dosages. In this poster, we describe the in-situ SEY measurement systems and the initial results on bare aluminum and TiN-coated aluminum samples.

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